

Notice of References Cited	Application/Control No. 10/584,218	Applicant(s)/Patent Under Reexamination MIYACHI ET AL.	
	Examiner Sean P. Cullen, Ph.D.	Art Unit 1725	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0061446	05-2002	Gan et al.	429/231.8
*	B	US-2003/0054249	03-2003	Yamamoto et al.	429/231.1
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

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